

Notice of References Cited	Application/Control No. 09/856,847	Applicant(s)/Patent Under Reexamination ODAGAWA ET AL.	
	Examiner Hien N Nguyen	Art Unit 2824	Page 1 of 1

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	B	US-6,219,275	04-2001	Nishimura, Naoki	365/173
	C	US-6,480,411	11-2002	Koganei, Akio	365/158
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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